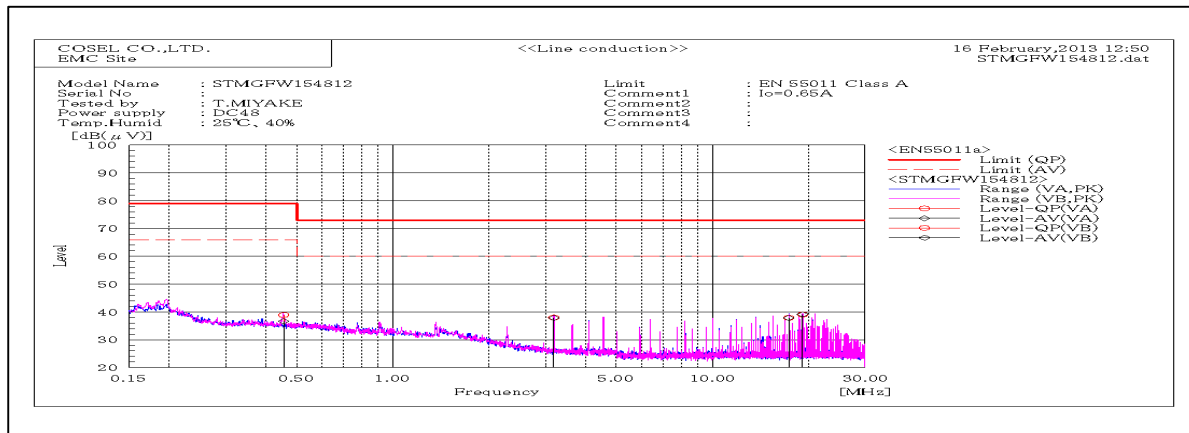
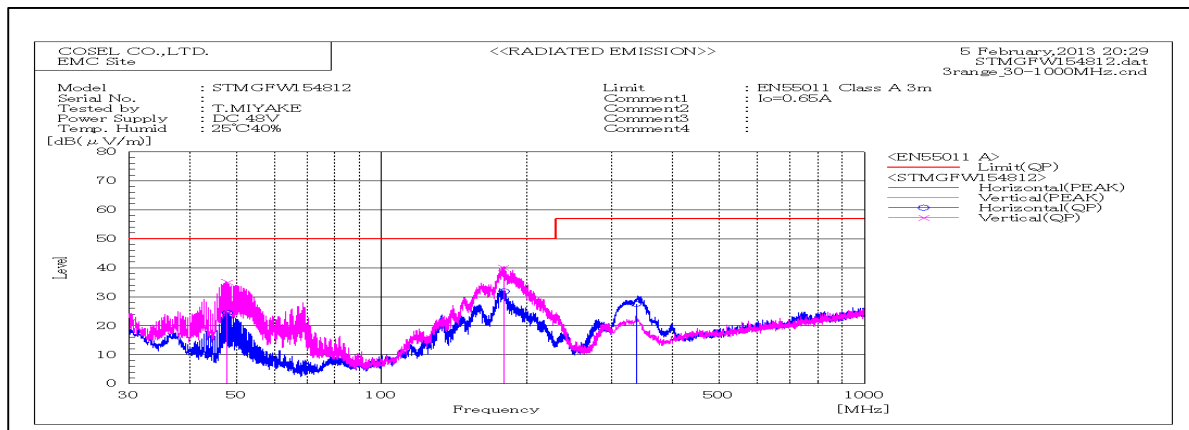


DATA SHEET		Date	18-Feb-13
Model	STMGFW154812	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Miyake



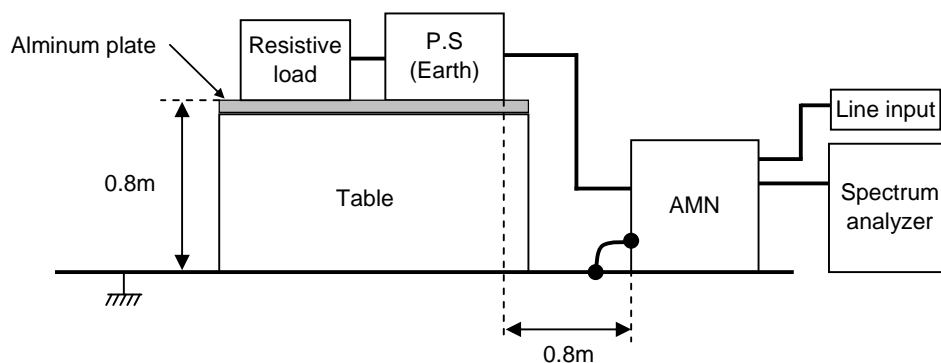
Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.45581		VB	18.8	16.5	20.1	38.9	36.6	79	66	40.1	29.4	Pass	
3.19074		VB	17.6	17.6	20.3	37.9	37.9	73	60	35.1	22.1	Pass	
17.3248		VA	16.7	16.6	21.2	37.9	37.8	73	60	35.1	22.2	Pass	
19.1472		VB	17.9	17.9	21.2	39.1	39.1	73	60	33.9	20.9	Pass	



Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV						
47.915	V	Stable	57.9		-22.9	35		50	15	Pass	101	85	
47.91	H	Stable	48		-23.5	24.5		50	25.5	Pass	147	104	
179.276	V	Stable	55.9		-16	39.9		50	10.1	Pass	101	278	
179.282	H	Stable	54.2		-22.3	31.9		50	18.1	Pass	157	102	
336.614	H	Stable	42.7		-15.2	27.5		57	29.5	Pass	108	84	

DATA SHEET		Date	18-Feb-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Miyake

## 1. Line conduction



## 2. Radiated emission

